AMENDMENTS TO THE CLAIMS

The following listing of claims will replace all prior versions, and listings, of claims in the application:

Listing of Claims:

1. (Previously Presented) An apparatus for managing a liquid crystal substrate, comprising:

a liquid crystal testing device operable to determine whether at least one of a panel and a substrate in the liquid crystal substrate has a defect, and acquire defect information indicative of at least the defect and whether the at least one of the panel and the substrate is defective;

a liquid crystal repair device operable to repair the defect based on the defect information, and acquire repair information that is indicative of whether the defect is actually repaired; and

a data management section having a database adapted to record the defect information which is acquired from the liquid crystal testing device, and the repair information which is acquired from the liquid crystal repair device, wherein:

said data management section is operable to redetermine the presence of the defect based on comparison between the defect information and the repair information which are recorded in said database,

said liquid crystal repair device is operable to correct the defect information to generate corrected defect information when the defect information is different from

the repair information with regard to the defect; and

said data management section is operable to update the defect information recorded in said database with the corrected defect information.

2. (Original) The liquid crystal substrate managing apparatus according to claim 1, wherein said data management section stores a recipe information for defining specifications of the substrate and panel in said database, said recipe information being edited freely.

3. (Original) The liquid crystal substrate managing apparatus according to claim 2, wherein said data management section edits the recipe information by exchange of information with a terminal connecting to the data management section.

4. (Currently Amended) A method for managing a liquid crystal substrate comprising:

determining whether at least one of a panel and a substrate in the liquid crystal substrate has a defect, and acquire defect information indicative of at least the defect and whether the at least one of the panel and the substrate is defective;

repairing the defect based on the defect information, and acquires repair information indicative of at least a position that is actually repaired;

recording, in a database, the defect information which is acquired from the a liquid crystal testing device, and the repair information which is acquired from the a liquid crystal repair device;

redetermining the presence of the defect based on comparison between the

defect information and the repair information which are recorded in the database;

correcting the defect information to generate corrected defect information

when the defect indicated by the defect information is different from the defect

indicated by the repair information with regard to the defect; and

updating the defect information recorded in said database with the corrected

defect information.

5. (Original) The liquid crystal substrate managing method according to

claim 4, further comprising:

recording a recipe information acquired from the liquid crystal testing device in

the database, the recipe information defining specifications of the substrate and

panel and being edited freely.

6. (Canceled)

7. (Previously Presented) The liquid crystal substrate managing apparatus

according to claim 1, wherein:

the repair information includes image information of a part of the at least one

of the panel and the substrate that is actually repaired.

8. (Previously Presented) The liquid crystal substrate managing apparatus

according to claim 1, wherein:

said data management section is operable to acquire trend information for

defects of a plurality of liquid crystal substrates, by applying statistical processing

with respect to the defect information and the repair information recorded in the database.

9. (Canceled)

10. (Previously Presented) The method for managing a liquid crystal substrate according to claim 4, wherein:

the repair information includes image information of a part of the at least one of the panel and the substrate that is actually repaired.

11. (Previously Presented) The method for managing a liquid crystal substrate according to claim 4, further comprising:

acquiring trend information for defects of a plurality of liquid crystal substrates, by applying statistical processing with respect to the defect information and the repair information recorded in the database.

12. (New) The liquid crystal substrate managing apparatus according to claim 1, wherein:

the corrected defect information is generated as a part of the repair information; and

the defect information is updated when the repair information includes the corrected defect information.

13. (New) The method for managing a liquid crystal substrate according to

claim 4, wherein:

the corrected defect information is generated as a part of the repair

information; and

the defect information is updated when the repair information includes the

corrected defect information.